

N-Channel 30-V (D-S) MOSFET

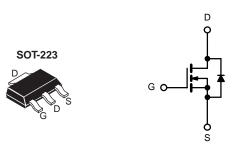
PRODU	CT SUMMARY		
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)
30	0.008 at V _{GS} = 10 V	13	6.1 nC
30	0.011 at V _{GS} = 4.5 V	11	0.1110

FEATURES

- · Halogen-free
- Trench Power MOSFET
- Optimized for High-Side Synchronous Rectifier Operation
- 100 % R_g Tested
- 100 % UIS Tested



- Notebook CPU Core
 - High-Side Switch



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS $T_A = 25 ^{\circ}C$, unless Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	30		
Gate-Source Voltage		V _{GS}	± 20		
<u> </u>	T _C = 25 °C		13		
Continuous Drain Current (T _{.1} = 150 °C)	$T_C = 70 ^{\circ}C$	I	10		
Continuous Diam Current (1) = 130 C)	T _A = 25 °C	I _D	9 ^{b, c}		
	T _A = 70 °C		7 ^{b, c}	^	
Pulsed Drain Current		I _{DM}	45	A	
Continuous Course Drain Diada Current	T _C = 25 °C	I-	3.7		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.0 ^{b, c}		
Single Pulse Avalanche Current		I _{AS}	20		
Avalanche Energy	L = 0.1 mH	E _{AS}	21	mJ	
	T _C = 25 °C		4.1		
Maximum Dayyar Dissination	T _C = 70 °C	D.	2.5	W	
Maximum Power Dissipation	T _A = 25 °C	P _D	2.2 ^{b, c}		
	T _A = 70 °C		1.3 ^{b, c}		
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	39	55	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	25	29	C/VV

Notes:

- a. Base on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.

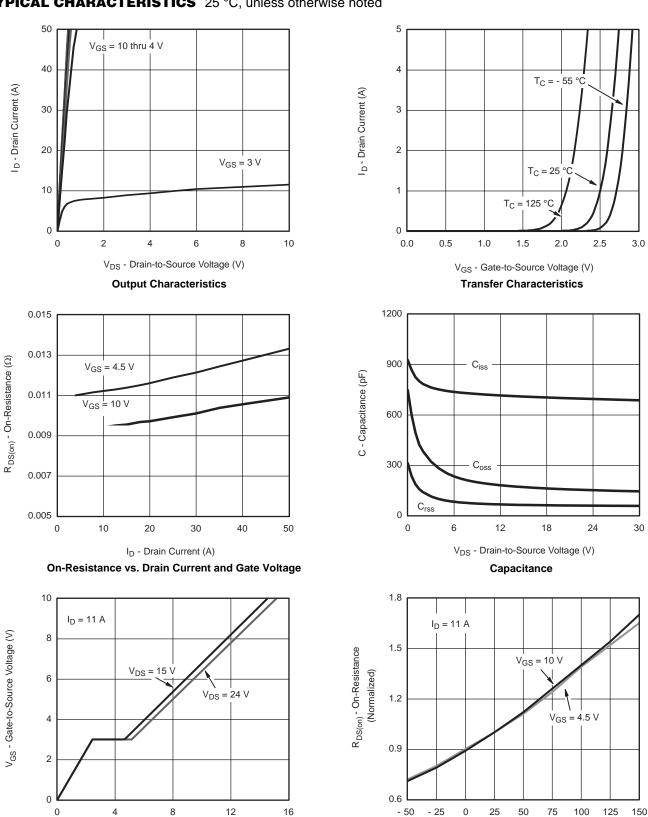


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250A		26		14/00
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.8		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
7 0 1 1/1 5 1 0 1	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V			1	μA
Zero Gate Voltage Drain Current		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α
Drain-Source On-State Resistance ^a	_	V _{GS} = 10 V, I _D = 10 A		0.008		Ω
	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 9 A		0.011		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 10 A		50		S
Dynamic ^b	<u> </u>				I	
Input Capacitance	C _{iss}			800		pF
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		165		
Reverse Transfer Capacitance	C _{rss}			73		
Total Gate Charge		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 10 A		15	23	
	Qg			6.8	10.2	nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 10 \text{ A}$		2.5		
Gate-Drain Charge	Q _{gd}			2.3		
Gate Resistance	R _g	f = 1 MHz	0.36	1.8	3.6	Ω
Turn-On Delay Time	t _{d(on)}			16	23	- ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.4 Ω		12	16	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		16	22	
Fall Time	t _f			10	18	
Turn-On Delay Time	t _{d(on)}			8	16	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.4 Ω		10	20	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	22	
Fall Time	t _f			8	15	
Drain-Source Body Diode Characterist	tics					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			10	٨
Pulse Diode Forward Current ^a	I _{SM}				50	A
Body Diode Voltage	V_{SD}	I _S = 9 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns
Body Diode Reverse Recovery Charge	Q _{rr}	L = 0 A dl/dt = 100 A/us T = 25 °C		6	12	nC
Reverse Recovery Fall Time	t _a			8		
Reverse Recovery Rise Time	t _b			7		ns

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$ b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





服务热线:400-655-8788

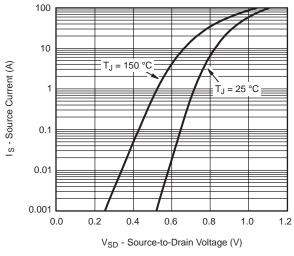
Q_q - Total Gate Charge (nC)

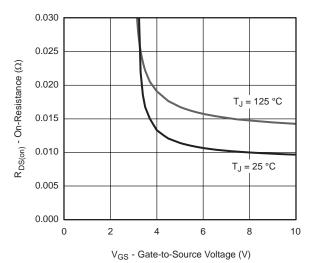
Gate Charge

T_J - Junction Temperature (°C)

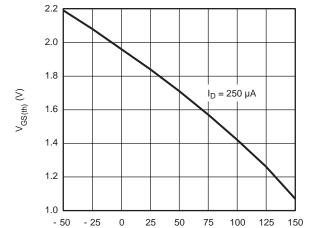
On-Resistance vs. Junction Temperature



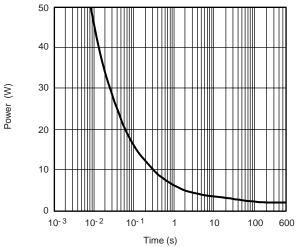




Source-Drain Diode Forward Voltage

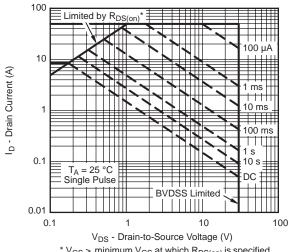


On-Resistance vs. Gate-to-Source Voltage



T_J - Temperature (°C) **Threshold Voltage**

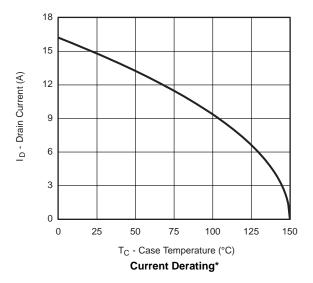


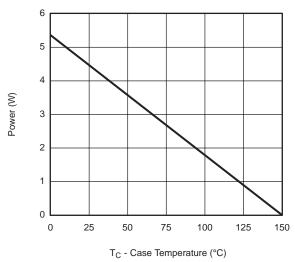


* $V_{GS} > \mbox{minimum } V_{GS}$ at which $R_{DS(on)}$ is specified

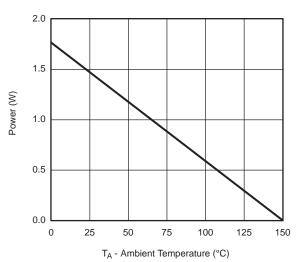
Safe Operating Area, Junction-to-Ambient







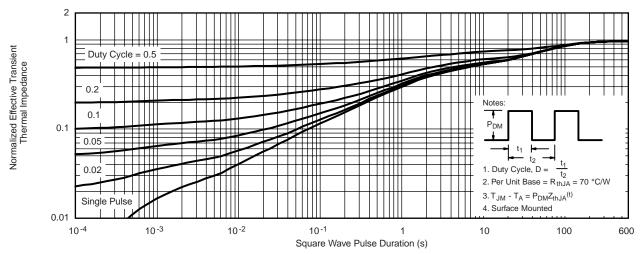
Power Derating, Junction-to-Foot



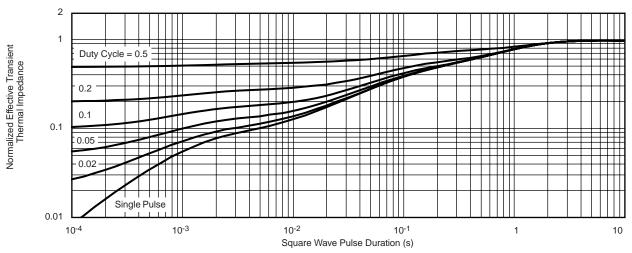
Power Derating, Junction-to-Ambient

* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





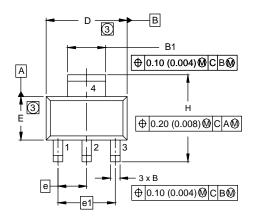
Normalized Thermal Transient Impedance, Junction-to-Ambient

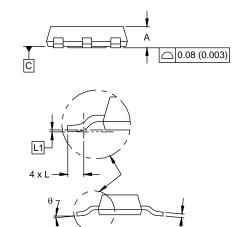


Normalized Thermal Transient Impedance, Junction-to-Foot



SOT-223





DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	1.55	1.80	0.061	0.071
В	0.65	0.85	0.026	0.033
B1	2.95	3.15	0.116	0.124
С	0.25	0.35	0.010	0.014
D	6.30	6.70	0.248	0.264
E	3.30	3.70	0.130	0.146
е	2.30 BSC		0.0905 BSC	
e1	4.60 BSC		0.181	BSC
Н	6.71	7.29	0.264	0.287
L	0.91	-	0.036	-
L1	0.061 BSC		0.0024	4 BSC
θ	-	10'	-	10'

ECN: S-82109-Rev. A, 15-Sep-08

DWG: 5969

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension do not include mold flash.
- 4. Outline conforms to JEDEC outline TO-261AA.

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